

Application/Control No.	Applicant(s)/Patent under Reexamination
09/497,522	SHIN ET AL.
Examiner	Art Unit
Nhon T. Diep	2613

SEARCHED					
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
Interfere	nce Sca	uh KBI	ony			
print-	ont	9/30/05	N.D.			

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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
60/118,750 (Fg.1)	9/18/05	M?		
RAO, ANDY	9/19/05	M.		
VO, TUNG	9/27/05			
LEE, MCHAMD	9/30/05	M.		
WI LE	9/20/05	İ		
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